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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/726,891	12/04/2003	Satoru Kamano	YMOR:300	4184
6160	7590	11/18/2004	EXAMINER	
PARKHURST & WENDEL, L.L.P. 1421 PRINCE STREET SUITE 210 ALEXANDRIA, VA 22314-2805			NGUYEN, TUNG X	
			ART UNIT	PAPER NUMBER
			2829	

DATE MAILED: 11/18/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

## Office Action Summary

Application No.

10/726,891

Applicant(s)

KAMANO ET AL.

Examiner

Tung X Nguyen

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

### Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

### Status

- 1) ☒ Responsive to communication(s) filed on 04 December 2003.
- 2a) ☐ This action is FINAL. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

### Disposition of Claims

- 4) ☒ Claim(s) 1-10 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1-10 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

### Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 04 December 2003 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

### Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some \* c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- \* See the attached detailed Office action for a list of the certified copies not received.

### Attachment(s)

- 1) ☒ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☒ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  
Paper No(s)/Mail Date 9/13/04, 12/04/03.
- 4) ☐ Interview Summary (PTO-413)  
Paper No(s)/Mail Date. \_\_\_\_\_.
- 5) ☐ Notice of Informal Patent Application (PTO-152)
- 6) ☐ Other: \_\_\_\_\_.

**DETAILED ACTION**

***Claim Rejections - 35 USC § 102***

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

2. Claims 1-10 are rejected under 35 U.S.C. 102(a) as being anticipated by Mori et al. (u.s.p 6,628,137).

As to claim 1, Mori et al. disclose in Figs. 1-4c, an ancillary equipment for testing a semiconductor integrated circuit comprising: a device measuring unit (21 of figure 4a) comprising a measuring section (23 of figure 4a), and an analyzing section (25 of figure 4a); wherein the measuring section (23) exchanging a signal with a measured device under test (DUT 11 of figure 4a), the analyzing section (25 of figure 4a) for analyzing the information from the measuring section by using a programmable device (26); and a control/communication card (20 of figure 1) comprising a board (20) different from the device measuring unit (21 of figure 4a); wherein the control/communication card (20 of figure 4a) being connected to the device measuring unit (23 of figure 4a) to control the device measuring unit and carrying out communication with a general-purpose computer (45, 46 of figure 1).

As to claim 2, Mori et al. disclose in Fig. 4a-4c, the control/communication card (20) includes a data input section (26) for acquiring data from the device measuring unit (23); a control signal output section (24) for transmitting a control signal to the device

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measuring unit (23), and an interface (28) for exchanging a signal with the general-purpose computer (45, 46).

As to claim 3, Mori et al. disclose in Figs. 4a-4c, the device measuring unit (21) includes a program writing port (28 of figure 1) to allow a program to be written on the programmable device (26) of the device measuring unit from the general-purpose computer (45-46 of figure 1, and 40e of figure 3).

As to claim 4, Mori et al. disclose in Figs. 4a-4c, the device measuring unit (21) or the control/communication card (20) comprises an observing terminal (28) for observing an input/output signal and an internal signal of the device measuring unit (21).

As to claim 5, Mori et al. disclose in Figs. 4a-4c, the device measuring unit (21) comprises a connector (28 of figure 1) for making connection via a cable with a substrate having a socket (12 of figure 4b) for mounting a device under test (DUT); and a connector (28 of figure 1) for directly making insertion into the substrate.

As to claim 6, Mori et al. disclose in Figs. 4a-4c, the device measuring unit (21) comprises a plurality of input terminals (28 of figure 1) for inputting signals from a plurality of circuits provided on the device under test (DUT).

As to claim 7, Mori et al. disclose in Figs. 4a-4c, the control/communication card (20 of figure 1) comprises a device measure diagnosing unit (23) for transmitting a diagnostic signal for diagnosing the device under test (DUT) to the device measuring unit (23) and transferring diagnostic result data from the device measuring unit to the general-purpose computer (45, 46 of figure 4a).

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As to claim 8, Mori et al. disclose in Figs. 4a-4c, a plurality of device measuring units (20, 21 of figure 1) are provided and a test can be conducted using one or more of the device measuring units (20, 21 of figure 1).

As to claim 9, Mori et al. disclose in Figs. 4a-4c, the device measuring unit (20 of figure 1) includes a program writing port (28 of figure 1) to allow a program to be written on the programmable device (26) of the device measuring unit from the general-purpose computer (45, 46 of figure 1, and 40 of figure 3), and the programmable device of the device measuring unit is a Flash-ROM (26).

As to claim 10, Mori et al. disclose in Figs. 4a-4c, a socket (12 of figure 4a) for mounting thereon with the device under test (DUT) is provided in the device measuring unit (20).

### ***Conclusion***

3. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Mori et al. (US 6456102 B1) related to apparatus and method for testing semiconductor integrated circuit.


4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tung X Nguyen whose telephone number is (571) 272-1967. The examiner can normally be reached on 8:30am-5:00pm M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Tokar can be reached on (571) 272-1812. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

TN  
11/09/04

  
DAVID ZARNEKE  
PRIMARY EXAMINER  
11/10/04